MN101E29 Series

Туре	MN101E29G	MN101EF29G
Internal ROM type	Mask ROM	FLASH
ROM (byte)	128K	128K+4K
RAM (byte)	6K	
Package (Lead-free)	LQFP100-P-1414, QFP100-P-1818B	
Minimum Instruction Execution Time	50 ns (at 2.2 V to 5.5 V, 20 MHz) *: at internal 2, 3, 4, 5, 6, 8, 10 times oscillation used	

■ Interrupts

6 external interrupts. 28 internal interrupts

RESET. NMI. External 0 to 4. Timer 0 to 4. Timer 6. Timer 7 (2 systems). Timer 8 (2 systems). Timer 9 (2 systems). Timer 9 (2 systems). 0 (2 systems). Serial 1 (2 systems). Serial 2 (2 systems). Serial 3 (2 systems). Serial 4. Serial 5. A/D conversion. Automatic transfer (2 systems). Key interrupt

■ Timer Counter

8-bit timer \times 7

,	o bit times x y	
	Timer 0Timer pulse output. Event count. Added pulse (2-bit) type PWM output. Remote control carrier output. Simple pulse width measurement. Real time output control	
	Timer 1Timer pulse output. Event count. 16-bit cascade connected (timer 0, 1). Timer synchronous output	
	Timer 2Timer pulse output. Event count. Added pulse (2-bit) type PWM output. Simple pulse width measurement. 24-bit cascade connected (timer 0, 1, 2). Timer synchronous output. Real time output control	
	Timer 3Timer pulse output. Event count. Remote control carrier output. 16-bit cascade connected (timer 2, 3). 32-bit cascade connected (timer 0, 1, 2, 3)	
	Timer 4Timer pulse output. Added pulse (2-bit) type PWM output. Event count. Serial transfer clock output. Simple puls width measurement	e
	Timer 68-bit freerun timer. Time base timer	
Timer AEvent count. Baud rate timer. Clock output for peripheral function		
	16-bit timer × 3	
	Timer 7Timer pulse output. Event count. High accuracy PWM. High performance IGBT output (cycle/duty continuous variable). Timer synchronous output. Input capture (both edge available). Real time output control. Double buffer compare register	ſ
	Timer 8Timer pulse output. Event count. High accuracy PWM output (cycle/duty continuous variable). Pulse width measurement. Input capture (both edge available). 32-bit cascade connected (timer 7, 8). 32-bit PWM output. Synchronous output event. Double buffer compare register	
	Timer 9Timer pulse output. Event count. High accuracy PWM output (cycle/duty continuous variable). Pulse width measurement. Input capture (both edge available). Real time output control. Double buffer compare register	

Watchdog timer \times 1

Synchronous type/UART (full-duplex) × 4: Serial 0 to 3

Synchronous type/Multi-master $I^2C \times 1$: Serial 4

 I^2C slave \times 1: Serial 5

■ DMA controller

■ Serial interface

2 systems. Maximum transfer cycles are 255

Starting factor: External request. Internal event. Software

■ I/O Pins

90: Common use. Specified pull-up/pull-down resistor available. Input/output selectable (bit unit) I/O

■ A/D converter

10-bit × 16 channels

■ D/A converter

8-bit × 4 channels

■ Display control function

LCD: 55 segments × 4 commons (Static, 1/2, 1/3, or 1/4 duty) 1/3 bias Usable if VLC1 ≤ VDD

> **Panasonic** MAD00062FEM

■ Special Ports

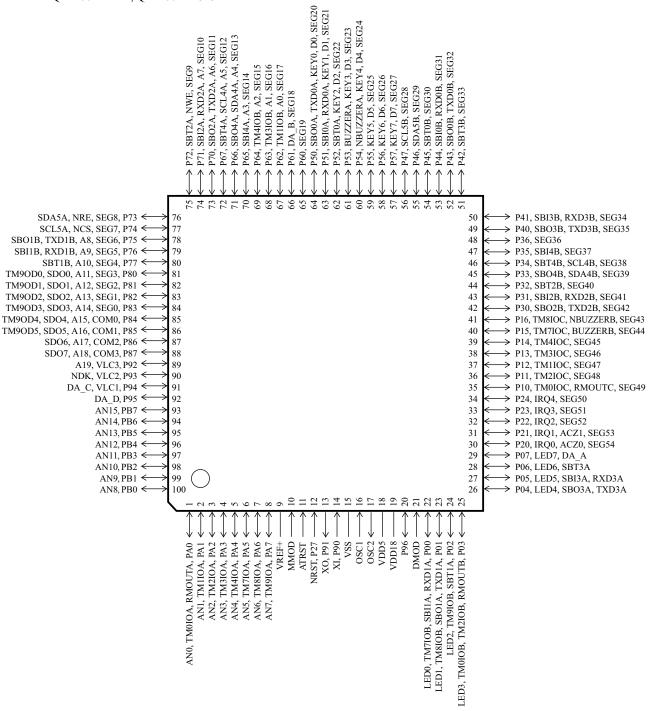
Buzzer output. Inverted buzzer output. Remote control carrier output. High-current drive port

■ ROM Correction

Correcting address designation: Up to 7 addresses possible

■ Pin Assignment

LQFP100-P-1414, QFP100-P-1818B



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